

<b>INFORMATION DISCLOSURE</b> <b>CITATION IN AN APPLICATION</b> (PTO-1449)				ATTY. DOCKET NO. <b>067161-0068</b>	SERIAL NO. <b>10/617,667</b>
APPLICANT <b>Jun SUMINO, et al.</b>				FILING DATE <b>July 14, 2003</b>	
GROUP <b>2822</b>					

  

U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
MP		US 6,566,224 B1	05-20-2003	Chang et al.		
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FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code <sup>1</sup> -Number + -Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes      No

  

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	
MP		Korean Office Action dated September 23, 2005 in corresponding Korean Application No. 10-2003-0066126	
MP		K. SHIMIZU, et al. "A Novel High-Density 5F <sup>2</sup> NAND STI Cell Technology Suitable for 256Mbit and 1Gbit Flash Memories," International Electron Device Meeting, <span style="background-color: black; color: black;">XXXX</span> 12/97	
MP		Surya BHATTACHARYA, "Improved Performance and Reliability of Split Gate Source-Side Injected Flash Memory Cells," International Electron Device Meeting, <span style="background-color: black; color: black;">XXXX</span> 12/96	

  

EXAMINER 	DATE CONSIDERED 12/05
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\*EXAMINER: Initial reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.



SHEET 1 OF 1

INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION

(PTO-1449)

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## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No
MP		CN 1345089 A	04-17-2002	SAMSUNG ELECTRONICS CO LTD	_____	CHINA (w/English Abstract) _____

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.

EXAMINER

DATE CONSIDERED

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